



**EA MLA Signatory**  
**Český institut pro akreditaci, o.p.s.**  
**Olšanská 54/3, 130 00 Praha 3**

issues

according to section 16 of Act No. 22/1997 Coll., on technical requirements for products, as amended

# CERTIFICATE OF ACCREDITATION

No. 599/2023

**Mitutoyo Česko s.r.o.**  
**with registered office Dubská 1626, 415 01 Teplice 1,**  
**Company Registration No. 25458400**

for the Calibration Laboratory No. 2390  
Calibration Laboratory

Scope of accreditation:

Calibration of meters in the field of length and plane angle to the extent as specified in the appendix to this Certificate.

This Certificate of Accreditation is a proof of Accreditation issued on the basis of assessment of fulfillment of the accreditation criteria in accordance with

ČSN EN ISO/IEC 17025:2018

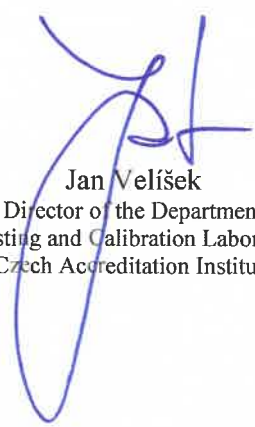
In its activities performed within the scope and for the period of validity of this Certificate, the Conformity Assessment Body is entitled to refer to this Certificate, provided that the accreditation is not suspended and the Accredited Body meets the specified accreditation requirements in accordance with the relevant regulations applicable to the activity of an accredited Conformity Assessment Body.

This Certificate of Accreditation replaces, to the full extent, Certificate No.: 305/2022 of 21. 6. 2022, or any administrative acts building upon it.

The Certificate of Accreditation is valid until: **3. 12. 2024**

Prague: 14. 11. 2023



  
**Jan Velišek**  
Director of the Department  
of Testing and Calibration Laboratories  
Czech Accreditation Institute

Accredited entity according to ČSN EN ISO/IEC 17025:2018:

Mitutoyo Česko s.r.o.  
CAB number 2390, Calibration Laboratory  
Dubská 1626, 415 01 Teplice 1

**CMC for the field of measured quantity: Length**

Ord. number <sup>1</sup>	Calibrated quantity / Subject of calibration	Nominal range		Parameter(s) of the measurand	Lowest stated expanded measurement uncertainty <sup>2</sup>	Calibration principle	Calibration procedure identification <sup>3</sup>	Work place
		min. unit	max. unit					
1*	Coordinate measuring machines (CMM)	0 m 0 m	to to 25 mm		(0.3L + 0.1) µm (0.6L + 0.3) µm 0.2 µm	measurement by a laser interferometer comparison using a step gauge comparison with a reference sphere	MCZ-PI-KL_SD15_KP01 (ČSN EN ISO 10360-2, ČSN EN ISO 10360-4, ČSN EN ISO 10360-5)	
2*	Surface roughness measuring instruments	0.1 µm 0.01 µm 0.1 µm -400 µm	to to to to 15 µm		3.4 % 2.4 % 0.6 % 4 µm 0.06 µm	comparison with a roughness standard comparison with UDT linearity standard comparison with an optical plane standard	MCZ-PI-KL_SD15_KP02 (ČSN EN ISO 3274, ČSN EN ISO 12179)	
3*	Surface profile measuring instruments	0 mm 0 mm -15 µm	to to to 15 µm	axes X, Y Z-axis	(0.3L + 0.2) µm (0.3L + 0.2) µm 0.06 µm	measurement by a laser interferometer comparison with a parallel gauge comparison with an optical plane standard	MCZ-PI-KL_SD15_KP02 (ČSN EN ISO 3274, ČSN EN ISO 12179)	



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Ord. number <sup>1</sup>	Calibrated quantity / Subject of calibration	Nominal range		Parameter(s) of the measurand	Lowest stated expanded measurement uncertainty <sup>2</sup>	Calibration principle	Calibration procedure identification <sup>3</sup>	Work place
		min. unit	max. unit					
4*	Profile projectors Parallellity P <sub>XY</sub> Cross hair position E <sub>CH</sub> Magnification error Measuring microscopes Parallellity P <sub>XY</sub>	0 mm to -200 µm -200 µm -1 %	200 mm 200 µm 200 µm 1 %		(8.9L + 1.2) µm 1 µm 4 µm 0.01 (abs.) (8.9L + 1.2) µm 1 µm	comparison with a glass rule	MCZ-PI-KL_SD15_KP03	
5*	1D measuring instruments (height gauges)	0 m to 0 m to	1 m 1 m		(0.23L + 0.05) µm (0.5L + 0.3) µm	measurement by a laser interferometer comparison using a step gauge	MCZ-PI-KL_SD15_KP04	
6*	Ring gauges Sensor linearity measurement error Spindle axial runout Spindle radial runout Cylindricity	-400 µm to -200 µm to -200 µm to 0 µm to	400 µm 200 µm 200 µm 200 µm		4 µm 0.02 µm 0.04 µm 1.8 µm	comparison with UDT linearity standard comparison with reference hemisphere comparison with reference hemisphere comparison with reference cylinder	MCZ-PI-KL_SD15_KP05	
7*	Coordinate measuring machines equipped with a camera system (VMM)	0 m to 0 m to	1 m 0.3 m	X, Y axis Z axis	(2,4L + 0,2) µm (3,1L + 0,3) µm	comparison with a glass rule comparison with a parallel gauge	MCZ-PI-KL_SD15_KP06	

<sup>1</sup> Asterisk at the ordinal number identifies the calibrations, which the Laboratory is qualified to carry out outside the permanent laboratory premises.

<sup>2</sup> The expanded measurement uncertainty is in accordance with ILAC-P14 and EA-4/02 M a part of CMC and it is the lowest value of the respective uncertainty. If not stated otherwise, its coverage probability is approx. 95 %. If not stated otherwise, the uncertainty values stated without a unit are relative to the measured value. The uncertainty value stated herein is based on the best conditions achievable by the laboratory; the uncertainty value of a specific calibration may be higher depending on the conditions of such a calibration. For identical extreme values of adjacent ranges, the lower uncertainty value always applies.

<sup>3</sup> If the document identifying the calibration procedure is dated only these specific procedures are used. If the document identifying the calibration procedure is not dated, the latest edition of the specified procedure is used (including any changes).

**Explanatory notes:**

L – Length in metres

Parallellity P<sub>XY</sub> – Parallellity of a cross table with a cross hair P<sub>XY</sub>



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**CMC for the field of measured quantity: Plane angle**

Ord. number	Calibrated quantity / Subject of calibration	Nominal range		Parameter(s) of the measurand	Lowest stated expanded measurement uncertainty <sup>2</sup>	Calibration principle	Calibration procedure identification <sup>3</sup>	Work place
		min. unit	max. unit					
1*	Error of angle measurement in the XZ plane / Surface profile measuring instruments		135 °		0.0034°	direct measurement of angle gauge 135°	MCZ-PI-KL_SD15_KP02 (ČSN EN ISO 3274, ČSN EN ISO 12179)	
2*	Angle measurement error -- 360° focus screen rotation / Profile projectors		360 °		0.5'	direct measurement of glass gauge position	MCZ-PI-KL_SD15_KP03	

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<sup>2</sup> The expanded measurement uncertainty is in accordance with ILAC-P14 and EA-4/02 M a part of CMC and it is the lowest value of the respective uncertainty. If not stated otherwise, its coverage probability is approx. 95 %. If not stated otherwise, the uncertainty values stated without a unit are relative to the measured value. The uncertainty value stated herein is based on the best conditions achievable by the laboratory; the uncertainty value of a specific calibration may be higher depending on the conditions of such a calibration. For identical extreme values of adjacent ranges, the lower uncertainty value always applies.

<sup>3</sup> If the document identifying the calibration procedure is dated only these specific procedures are used. If the document identifying the calibration procedure is not dated, the latest edition of the specified procedure is used (including any changes).

